

## REMARKS

Claims 1-20 have been cancelled. Claim 23 has been added. Claim 23 remains for further consideration. No new matter has been added.

The objections and rejections shall be taken up in the order presented in the Official Action.

1. The Official Action contends that the priority document has not yet been submitted. However, the prior document DE 103 05 972.5 was submitted to the USPTO on July 13, 2004 along with a Certificate of First Class mailing. Attached please find a copy of the postcard indicating the USPTO's receipt of the prior document and a copy of the cover page of the priority document.

2. Entry of the IDS is noted and appreciated.

3. A replacement Abstract is enclosed.

4. Claims 1-20 currently stand rejected under 35 U.S.C. §112, second paragraph for allegedly failing to particularly point out and distinctly claim the subject matter deemed to be the present invention.

Claims 1-20 have been cancelled.

5. Claims 1-20 currently stand rejected for allegedly being anticipated by the subject matter disclosed in U.S. Patent 6,639,537 to Raz (hereinafter "Raz").

Claims 1-20 have been cancelled. Claim 23 has been added. Claim 23 recites a system for compensating for distortion within an analog-to-digital converter. The system includes:

“a test signal generator that provides an analog test signal and a digitized test signal indicative of the analog test signal;  
an analog-to-digital converter that selectively receives an input signal and the analog test signal and provides a digitized signal;  
a compensation circuit that receives the digitized signal and adaptive filter coefficients, and provides a compensated digitized signal;  
a test signal check device that receives and processes the compensated digital signal to extract a sequence of output data;  
a difference unit that receives the sequence of output data and the compensated digital signal and provides a difference signal indicative of the difference; and  
a coefficient determination unit that receives the difference signal and the digitized signal and provides adaptive filter coefficients.” (emphasis added, cl. 23).

Raz neither discloses such a test signal check device that processes the compensated digital signal to extract a sequence of output data is compared in a difference unit with the compensated digital signal in order to provide a difference signal that is used to compute the adaptive filter coefficients. Accordingly, it is respectfully submitted that Raz is incapable of anticipating or rendering obvious the subject matter recited in claim 23.

For all the foregoing reasons, reconsideration and allowance of claim 23 is respectfully requested.

If a telephone interview could assist in the prosecution of this application, please call the undersigned attorney.

Respectfully submitted,



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## **KCOMPENSATION CIRCUIT AND ~~COMPENSATION~~ METHOD TO COMPENSATE NONLINEAR DISTORTIONS OF AN A/D CONVERTER**

### **BACKGROUND OF THE INVENTION**

The invention relates to the field of analog-to-digital signal conversion, and in particular to a compensation circuit to compensate nonlinear distortions of an analog-to-digital (A/D) converter, (A/D: analog/digital) having the features listed in the preamble of Claim 1, and to a compensation method to compensate nonlinear distortions of an A/D converter.

A/D converters are a critical component in integrated circuits having mixed signal processing, (i.e., analog and digital signal processing). Requirements related to the linearity of the A/D converter are quite difficult to achieve given the usual tolerances for analog components. The measures required for this purpose in the area of analog design entail high cost and/or high current consumption by the circuit.

In order to prevent nonlinear distortions in the analog-to-digital conversion process of the A/D converter, compensation circuits are employed to compensate for these nonlinear distortions of the A/D converter. ~~These compensation circuits haveing an analog signal input, and are typically located. Usually, they are a component~~ on the input side of the A/D converter.

~~The goal of the invention is therefore to propose~~ There is a need for a compensation circuit that to compensates for nonlinear distortions of an A/D converter, and requires a which circuit ~~provides for a~~ simplified overall analog design together with, preferably, reduced current consumption.

### **SUMMARY OF THE INVENTION**

~~This goal is achieved by a compensation circuit to compensate nonlinear distortions of an A/D converter having the features of Claim 1 and by a method to compensate nonlinear distortions of an A/D converter having the features of Claim 18.~~

A compensation circuit to compensate nonlinear distortions of an A/D converter may include advantageously have a signal input and a compensation circuit composed of digital circuit elements to digitally compensate nonlinear distortions, the signal input as the compensation input being a digital signal input to supply a signal outputted in distorted form by the A/D converter. Implementation is thus in the form of an output-side digital compensation or distortion correction of the nonlinear distortions from an input-side A/D converter. The digital circuit elements required for this purpose are inexpensive and readily available based on a simple digital circuit design. Advantageously, it is no longer necessary to incur high costs or have increased current consumption based on a compensation circuit added on the input-side of, or integrated into, the A/D converter.

~~According to the method, after analog to digital conversion within the A/D converter and a nonlinearly distorted digital signal is outputted, compensation is implemented in the digital circuit segment.~~

~~Advantageous embodiments are the subject of the dependent claims.~~

## **BRIEF DESCRIPTION OF THE DRAWINGS**

~~An embodiment and modifications thereof will be explained in greater detail with reference to the drawing.~~

~~Figure FIG. 1 is a block diagram illustration of a shows basic elements of the compensation circuit to compensate for nonlinear distortions of an A/D converter;~~

~~FIG. figure 2 is a block diagram illustration of shows a circuit to determine a test signal;~~

FIG. figure 3 is a block diagram illustration of shows-a circuit for the iterative calculation of correction coefficients; and

FIG. figure 4 is a block diagram illustration of shows-an alternative circuit for the iterative calculation of correction coefficients using a look-up table.

### **DETAILED DESCRIPTION OF THE INVENTION**

FIG. 1 is a block diagram illustration of a compensation circuit to compensate for nonlinear distortions of an A/D converter. ~~As is evident from Figure 1,~~ The compensation circuit in the example is composed of an analog section, shown at left, and a digital section shown on the right. An analog input signal  $x(t)$  is supplied to an A/D converter ADC/1, which provides (A/D: analog-to-digital). ~~After analog-to-digital conversion,~~ a digital sequence of characters  $x_n$  ~~is outputted from the output of A/D converter 1, which sequence~~ correspondings to the analog input signal  $x(t)$ . When a conventional A/D converter 1 is used, the digital sequence  $x_n$  from this converter exhibits nonlinear distortion. The index  $n$  represents the sequence of sampling values  $x_n$ ,  $n = 0, 1, 2, \dots$

The A/D-converted sequence  $x_n$  ~~is then fed to the input of a compensation circuit 2.~~ Compensation circuit 2 ~~which~~ compensates or corrects the nonlinear distortion ~~which has been created by the A/D converter 1.~~ The compensation circuit 2 provides ~~Finally, a sequence of compensated digital data  $y_n$  is outputted from compensation circuit 2 as the output data sequence.~~

~~In order to be able to implement the compensation,~~ The compensation circuit 2 receives coefficients  $c_1, c_2, \dots c_K, c_0$  ~~are supplied to compensation circuit 2 which~~ that have been determined or calculated based on the nonlinear distortion response of the A/D converter 1. The index  $k = 1, 2, \dots, K$  here functions as the consecutive index for the coefficients  $c_k$  of compensation.

The circuit of this design ~~includes an consisting of~~ A/D converter 1 together with the following compensation circuit 2 to which a set of coefficients  $c_1, \dots, c_K$  is supplied ~~thus offers a~~ simple design which enables an analog-to-digital conversion of an analog signal  $x(t)$  to form a sequence of compensated digital data  $y_n$  which does not suffer from nonlinear distortion.

~~Additional components of the circuit, shown in the segment enclosed by the broken line, serve the purpose of~~ A coefficient computation unit 100 ~~determines~~ the coefficients  $c_1, \dots, c_K$ .

These additional components are advantageously active only during a configuration phase. As an alternative to the circuit described below, it is also possible to employ a memory in which a set of coefficients  $c_1, \dots, c_K$ , determined previously only once, is stored which may be applied generally for the compensation. ~~However, The preferred approach, however,~~ is the circuit design described below which provides an adjustment of the coefficients  $c_1, \dots, c_K$  to the actual and/or instantaneous conditions.

Referring to FIG. 1, ~~In the circuit shown in the example,~~ a test signal  $s(t)$  is generated by a test signal generator 3 and applied during the configuration phase to the input of the A/D converter 1. ~~The~~ The test signal generator 3 also provides either the parameters  $s_n$  to generate the analog test signal  $s(t)$  or a sequence of digital test signal data  $S_n$  corresponding to this analog test signal  $s(t)$ . These parameters  $s_n$  or test signal data  $S_n$  are fed to a coefficient determination system 5 and/or to a test signal check device 4.

~~In addition, the circuit has a~~ The coefficient determination system 5 ~~to determines~~ the coefficients  $c_1, \dots, c_K$  to be used by the compensation circuit 2. ~~In addition to an output to transmit the determined coefficients  $c_1, \dots, c_K, c_0$  to compensation circuit 2,~~ The coefficient determination system 5 receives the ~~has an input to which the sequence of digital data  $x_n$  from the A/D converter 1, is supplied.~~ In addition, The coefficient determination system 5 also receives ~~has an input to which~~

distortion data or difference data  $D_n$  on a line 102 ~~are supplied~~. The difference data  $D_n$  are provided by a subtracter 6 to which the sequence of the compensated digital data  $y_n$  is fed from the output of the compensation circuit 2. The ~~S~~subtracter 6 also receives a sequence of digital signal data  $S_n$  either directly or indirectly through the test signal check device 4. The sequence of digital signal data  $S_n$  corresponds in the configuration phase to a signal map of the test signal, whereby, after appropriate determination of coefficients has been effected, this signal map is as undistorted as possible, or ideally is completely undistorted.

During the configuration phase, the analog test signal  $s(t)$  is ~~thus~~ generated and fed to the A/D converter 1. ~~The converter implements an analog-to-digital conversion for which provides the~~ sequence of digital data  $x_n$  ~~that is supplied both to~~ the compensation circuit 2 and the coefficient determination circuit 5. If the set of coefficients  $c_1, \dots, c_K$  is not available, the compensation circuit 2 outputs the sequence of digital data  $x_n = y_n$  as the sequence of compensated digital data  $y_n$  (i.e.,  $y_n = x_n$ ). This data is fed to the subtracter 6, which ~~that~~ is also supplied with a corresponding sequence of digital test signal data  $S_n$  ~~which matches~~ an undistorted data set. After subtraction of the two sequences of data  $(y_n - S_n)$ , the data sequence of the difference signal  $D_n$  on a line 102 is supplied to the coefficient determination system 5. ~~Using this data, coefficient determination system 5 determines the set of coefficients  $c_1, \dots, c_K, c_0$  that is supplied to compensation circuit 2 for future compensation.~~

According to a ~~the~~ preferred embodiment, a test signal  $s(t)$  is subsequently sent by the test signal generator 3, which may also be composed of a memory with an analog test signal  $s(t)$  and a corresponding digital parameter set  $s_n$ , to the A/D converter 1. The sequence of digital data  $x_n$  generated by the A/D converter 1 is subsequently compensated by the compensation circuit 2 in accordance with this supplied set of coefficients  $c_1, \dots, c_K$ , such that the sequence of compensated

digital data  $y_n$  is outputted, ideally with already optimized coefficients  $c_1, \dots c_K$ , without nonlinear distortion. The sequence of compensated digital data  $y_n$  is in turn fed to the subtracter 6 in which, after subtraction using the corresponding values of the sequence of digital test signal data  $S_n$ , the sequence of data  $D_n$  of the difference signal is again generated. This difference data  $D_n$  is again fed to the coefficient determination system 5 which, in the event difference data  $D_n$  does not equal zero or exceeds predetermined threshold values, implements another, or preferably, an iteratively improved determination of coefficients so as to provide improved coefficients  $c_1, \dots c_K$ .

After a sufficiently distortion-corrected or compensated set of coefficients  $c_1, \dots c_K$  has been determined, the configuration phase ends, after which the circuit composed of the A/D converter 1 and the compensation circuit 2 implements a conversion and compensation of the analog signal  $x(t)$  to form a sequence of compensated digital data  $y_n$ .

~~Appropriately, a~~ A configuration phase is initiated at regular intervals ~~in order to~~ check the set of coefficients used,  $c_1, \dots c_K$  in terms of their current validity. In this way, drifting nonlinear distortions caused, for example, by the circuit heating up or other interfering effects from the environment can be compensated.

The configuration phase is turned on and off ~~a sufficient number of times as needed~~ so that any slow changes in nonlinear distortions can be detected early enough and then compensated. It is, of course, in principle also possible to implement a predetermination and consideration of anticipated additional degradations or improvements related to the generation of distortions.

A control device 104 C is advantageously employed to control the compensation circuit, the control device 104 being connected to a time-monitoring device, specifically, a timer 106 T. In addition to turning the configuration phase on and off, the control device 104 C also controls the individual components through, for example, a bus 7.



In particular, it is possible to provide different types of test signals  $s(t)$ ,  $s_n$  for different application areas of the circuit so that coefficients  $c_1, \dots, c_K$  may, for example, be optimally adjusted for a low-frequency or high-frequency analog signal  $x(t)$ .

The following discussion examines in more detail the circuit components and the operational sequences of the method with reference to the mathematical background.

The configuration phase starts with an analog test signal

——— $s(t)$ ,

to which the theoretical uncorrupted sampling values

$$S_n = s\left(\frac{n}{F_s}\right),$$

correspond after analog-to-digital conversion, without nonlinear distortion, which values are in turn to be outputted after optimal compensation from the compensation circuit 2 as the sequence of compensated digital data  $y_n$ . Here  $n$  is a consecutive index of the set of natural numbers, while  $F_s$  is the sampling frequency of the A/D converter 1.

After ~~the analog test signal  $s(t)$  to A/D has been fed to converter 1 and the analog-to-digital conversion has been performed~~ on the analog test signal  $s(t)$  in the converter, the sequence of digital data  $x_n$  is supplied to its output based according to the expression

$$x_n = s_n + d_n.$$

The sequence of digital data  $x_n$  thus corresponds to the summation of correct theoretical and uncorrupted sampling values  $s_n$ , and the respective distortion data value  $d_n$  which matches the corresponding distortion by the A/D converter 1.

The ~~D~~digital compensation circuit 2 which uses the coefficients  $c_1, \dots, c_K$  to generate the sequence of compensated digital signals  $y_n$  that are ultimately to be outputted must therefore perform a compensation having the characteristic that ~~which~~ may be described by a  $K^{\text{th}}$ -order polynomial:

$$(1) \quad y_n = \sum_{k=1}^K c_k \cdot x_n^k = v \cdot s_n + D_n = S_n + D_n.$$

Here the coefficient values  $c_k$  with  $k = 1, 2, \dots, K$  are adaptive coefficients, that is, i.e., coefficients which may be adjusted as necessary. The output signal, or sequence of outputted compensated digital data  $y_n$  contains a map of the test signal or of the sequence of digital test signal data  $S_n$  plus a possible change  $v$ , specifically, amplification or ~~distortion~~-attenuation. The sequence of compensated digital data  $S_n$  is thus the product of a distortion factor  $v$  and the sequence of digital test signal data  $s_n$  which may be described by

$$S_n = v \cdot s_n,$$

where the effective distortions of the switching sequence of the A/D converter 1 and, in the event of insufficient compensation, of the compensation circuit 2 may be described by the sequence of difference data  $D_n$  according to the expression

$$(2) \quad D_n = y_n - S_n.$$

Since the parameters  $s_n$  of the test signal are known, the sequence of output signal data  $S_n$  may be extracted from the sequence of compensated digital data  $y_n$  by the test signal check device 4 so as to enable the actual distortion data or difference data  $D_n$  in data  $y_n$  to be calculated at the output of the compensation circuit 2. In addition, the gradients of the rms distortion may be calculated using the expression

$$\frac{\partial D_n^2}{\partial c_k} = 2 \cdot (y_n - S_n) \cdot x_n^k = 2 \cdot D_n \cdot x_n^k.$$

The use of an iterative method allows the set of coefficients  $c_k$  to converge. To this end, the formulation

$$(3) \quad c_k^{n+1} = c_k^n - G \cdot D_n \cdot x_n^k$$

may be selected so as ultimately to minimize the rms distortion or output. A parameter  $G$  is introduced in equation (3) as a stability criterion, which parameter at the same time provides for the highest possible convergence rate. The term  $c_k^n$  here describes the value of the coefficients  $c_k$  in the  $n^{\text{th}}$  iteration step, the coefficient of compensation  $c_k$  again having the consecutive index  $k = 1, \dots, K$ . The iteration steps are preferably counted from the value zero, so that  $n = 0, 1, \dots$ .

In an especially preferred embodiment, a sinusoidal test signal  $s(t) = \sin[2\pi t]$  is preferably used as the test signal to perform the nonlinear compensation since it is then simpler for the A/D converter 1 to determine the structure of the distortions, and is possibly simpler for the compensation circuit 2 to determine additional distortions. A nonlinearly distorting A/D converter 1 having a sinusoidal input signal at a frequency  $F_t$  produces harmonics on frequencies  $p \cdot F_t$ , which may be folded back by sampling to form

$$f_k = \begin{cases} (p \cdot F_t)_{\text{mod } F_s} & (p \cdot F_t)_{\text{mod } F_s} \leq \frac{F_s}{2} \\ F_s - (p \cdot F_t)_{\text{mod } F_s} & (p \cdot F_t)_{\text{mod } F_s} \geq \frac{F_s}{2} \end{cases}$$

Here  $p = 2, 3, \dots, M$  is the consecutive index of the frequency calculation.

If the first harmonics are significant, specifically, if  $p = 2, \dots, M$  applies, the test frequency  $F_t$  should be selected such that the frequency band  $2B$  is maximized around the fundamental where none of the first  $M$  harmonics fold back according to the expression

$$(4) \quad B = \max_{F_t} \left\{ \min_{p=2, \dots, M} \{ |F_t - fp| \} \right\}.$$

The extraction of the test signal or sequence of output signal data  $S_n$  may be implemented using a known method of carrier processing. Another factor which must be taken into account is that

the test signal  $s(t)$  or the sequence of output signal data  $S_n$  assigned to this signal are amplitude-conforming.

To this end, a circuit may be used that is based on an I/Q demodulator (I: in-phase, Q: quadrature phase) and a Cordic circuit 43, and calculates the phase and amplitude of the input sequence of digital data  $y_n$ . ~~FIG. The illustration in Figure-2~~ provides an example of this circuit.

Frequency, amplitude and direct current (DC) are recovered by feedback using the method known from automatic control engineering. A proportional and integral (PI) control ~~complete PI control (PI: proportional and integral components)~~ is employed here to determine the frequency. To determine amplitude and direct current, a TPI-control is used in which only the proportional components are employed. The control parameters used are the P-component of the amplitude control  $C_a$ , the P-component for the DC components  $C_{dc}$ , and the P-component and I-component of the frequency control  $C_p$  or  $C_i$ , which components are intended at the same time to meet the stability criterion for a control loop and to ensure the fastest possible transient.

~~The sequence of digital data  $y_n$  outputted by compensation circuit 2 is fed to a test signal check device 4,~~ The supplied sequence of digital data  $y_n$  is input to being fed to two multipliers 41a, 41b. A sinusoidal signal  $\sin[2\pi t]$  as the signal sequence to be multiplied is fed to the first of the multipliers 41a by a sinusoidal tone generator 41. Analogously, a cosine ~~cosinusoidal~~ signal sequence  $\cos[2\pi t]$  is supplied by the sinusoidal tone generator to the second multiplier 41b. After multiplication, the two data sequences are each fed to an associated filter 42a, 42b, respectively, ~~filter 42-~~ with undersampling P. After filtering, the I-separated and Q-separated signal components are supplied to a Cordic circuit 43 which determines, ~~for the data  $y_n$  outputted from compensation circuit 2,~~ a corresponding amplitude and corresponding phase that are supplied through two outputs.

The ~~signal sequence and data sequence~~ representing the amplitude is input to a subtractor 44a, which also receives a feedback signal on a line 202. The subtractor 44a provides a difference signal to multiplier 44b, which multiplies the difference signal by a coefficient value  $C_a$ , and the resultant product is output to a summer 44c. The summer 44c sums the product with the past value. The summer 44c provides a signal sequence to a delay element 44d, which provides a signal sequence to a delay element 44d, which provides an output signal to a multiplier 44e. The multiplier 44e also receives a cosine signal  $\cos[2\pi t]$  and provides the resultant product on a line 204. ~~are fed to a series of components 44. These are composed of a subtractor 44a, a multiplier 44b, an adder 44c, and an inverter ( $z^{-1}$ ) 44e, the output signal of which is fed to subtractor 44a and adder 44c. A coefficient value  $C_a$  is supplied as the control parameter for the P-component of amplitude control to the multiplier. The output signal of this series of components is also supplied to another multiplier 44e, to the input of which the cosinusoidal signal  $\cos[2\pi t]$  from sinusoidal tone generator 41 is applied. This system is ultimately used to determine the sequence of output signal data  $S_n$  that is then supplied to the difference-forming subtractor 6, which in turn has the sequence of digital data  $y_n$  applied to it through the second input.~~

~~In addition to amplitude,~~ The Cordic circuit 43 also outputs a corresponding phase or sequence of phase data on a line 206. This data is also fed to a circuit composed of a plurality of components 45. In the embodiment shown, this circuit is composed of two parallel multipliers 45b, 45a to which additionally a coefficient value  $C_p$  or a coefficient value  $C_i$  is supplied. The output signal of the ~~last named~~ multiplier 45a is fed to an adder 45c, the output signal of which is supplied both to an inverter ( $z^{-1}$ ) 45d and to a second adder 45e. The output signal of the inverter 45d is fed to the second input of the ~~first named~~ adder 45c. Through another input, the second adder 45e receives data from the multiplier 45b in which coefficient value  $C_p$  is up-multiplied for the phase data. The

output data from this adder 45e are fed to another adder 45f which has two additional inputs. A frequency ratio  $F_i/F_s$  ~~including~~ consisting of the test frequency  $F_t$  of the A/D converter 1 and the sampling frequency is supplied through the first additional input. An output value of the inverter ( $z^{-1}$ ) 45g connected after the adder 45f is fed through the second input. Output values of this inverter 45g are supplied as the timing variable  $t$  to an input of the sinusoidal tone generator 41.

In addition, a DC component  $DC_n$  is filtered out and extracted from the sequence of digital compensated data  $y_n$  outputted from the compensation circuit 2. To this end, the digital compensated data  $y_n$  are supplied to a circuit 46 composed of a subtracter 46a, a multiplier 46b, a adder 46c, and an inverter ( $z^{-1}$ ) 46d. A control parameter  $C_{dc}$  is applied through the second input to the multiplier 46b. Control parameter  $C_{dc}$  determines the rate of the transient. The outputted data sequence from the inverter 46d is supplied to the inputs of the subtracter 46a and the adder 46c, as well as to the subtracter 6 generating the difference data  $D_n$ .

~~In the circuit of~~ Referring to FIG. figure 2, the frequency  $F_t$  is thus derived using a phase-locked loop (PLL). The input signal corresponding to the sequence of compensated digital data  $y_n$  is split into I-component and Q-component that are then filtered by ~~a~~ the low-pass filter 42 of critical frequency  $B$  and undersampled. From the filtered I-component and Q-component, the Cordic circuit 43 then computes the amplitude and phase between input signal  $y_n$  and the locally generated sinusoidal tone from the sinusoidal tone generator 41. The phase is passed to the PI control as the error signal. After a settling time, the sinusoidal tone generator 41 ~~will generate~~ generates in its cosine branch a signal synchronized with the test tone. The ~~C~~ coefficients  $C_p$  and  $C_i$ , and test frequency  $F_t$  as the known parameters determine the PI control.

The amplitude is derived iteratively from the amplitude output of the Cordic circuit 43 using the control parameter  $C_a$ . The DC components are filtered and extracted from the output signal using

control parameter  $C_{dc}$ . The complete circuit composed of the test signal check device 4 (FIG. 1) and following the subtracter 6 (FIG. 1) finally generates a sequence of difference data  $D_n$  according to equation (3) proportional to the nonlinear distortions.

Advantageously, available carrier-processing systems and carrier-processing methods may be utilized for the purpose of implementing this circuit. What must be added are the circuits for the amplitude and DC components.

An especially preferred embodiment of compensation circuit 2 is constructed segment-by-segment, as shown in FIG. figure 3.

The data sequence  $x_n$  outputted by the A/D converter 1 is input to the ~~fed in~~ compensation circuit 2 to a parallel system of multipliers 21. At the same time, the same input signal, i.e., once again the corresponding data value of data sequence  $x_n$ , is fed to the second input of first multiplier 21<sub>2</sub> so that a squaring is effected. The output of this first multiplier 21<sub>2</sub> is supplied to the input of the second multiplier 21<sub>3</sub>, and so on, such that at each subsequent stage the exponent is increased by the value one up to a value  $x_n^K$ .

As a result, an exponentiation is effected, where each exponentiation step has an output so that values for digital data with exponentiations  $x_n^1, x_n^2, \dots, x_n^K$  are outputted from the input and the field of the multipliers 21. These are then fed to another field of multipliers 22, whereby a multiplication is performed with one each of the corresponding coefficients  $e_k(m)c_k(m)$  where  $k = 1, 2, \dots, K$ . What is described is thus a multi-element system with the coefficients  $c_k(m)$  of the compensation in the  $m^{\text{th}}$  segment with  $m = 0, 1, 2, \dots, N-1$  as the  $m^{\text{th}}$  segment of the amplitude range. Accordingly, the nonexponentiated value or nonexponentiated data sequence  $x_n^1$  as well as the coefficient  $c_1(m)$  are entered in the first multiplier 22<sub>1</sub> of the second multiplication field 22. The once exponentiated data value  $x_n^2$  and the second coefficient  $c_2(m)$  are entered in the second



multiplier 22<sub>2</sub>, etc. The output values of the multipliers 22<sub>1</sub>, 22<sub>2</sub>, ..., 22<sub>K</sub> of second multiplication field 22 are fed to an adder 23 which performs an addition of all input values, and also of the zero<sup>th</sup> coefficient  $c_0(m)$ , then outputs the sequence of compensated digital data  $y_n$ .

The sequence of digital data  $x_n$  outputted by the A/D converter 1 is also fed to the a coefficient determination system 5, where a rounding operation is performed in an index determination device 51, taking into account the N segments during the determination of the index m. Here the sequence of digital data  $x_n$  with its respective value increased by ±one is divided by 2two, then multiplied by the number of segments N. The thus generated segment index m on a line 302 is fed to a coefficient memory system 52 that is composed of a plurality of m parallel memory components 52<sub>0</sub>, 52<sub>1</sub>, ..., 52<sub>N-1</sub>. The respective coefficients  $c_1(m)$ ,  $c_2(m)$ , ...,  $c_K(m)$  and  $c_0(m)$  are stored in the individual segments of this coefficient memory system 52. For each stored index m, there is an output to an adder 53<sub>1</sub>, 53<sub>2</sub>, ..., 53<sub>K</sub>, 53<sub>0</sub>, the output of which in turn is fed back to the same segment of coefficient memory system 52. The result from a multiplier 54<sub>1</sub>, 54<sub>2</sub>, ..., 54<sub>K</sub> is entered in the second input of the adders 53<sub>1</sub>, ... . Each correspondingly exponentiated value of the sequence of digital data  $x_n^1$ ,  $x_n^2$ , ...,  $x_n^K$  is fed to the inputs of these multipliers 54<sub>1</sub>, 54<sub>2</sub>, ..., 54<sub>K</sub>. Supplied to each second input of the multipliers 54<sub>1</sub>, 54<sub>2</sub>, ..., 54<sub>K</sub> is the result of a multiplier 55 to which both the corresponding values for difference data  $D_n$  and the negative parameter -G serving as the stability criterion are supplied. Only the value for the difference data  $D_n$ , multiplied by the negative parameter -G, is supplied to the adder 53<sub>0</sub> at the adder's second input.

Using a circuit of this type, the compensation circuit 2 may be implemented on a segment-by-segment basis. The range of input data values, that is, the sequence of digital data  $x_n$ , from the A/D converter 1 with data values from -1 to +1 is, uniformly distributed among N segments according to the expression

$$-1 + \frac{2}{N}m \leq x_n \leq -1 + \frac{2}{N}(m+1),$$

where the segment index  $m$  lies between 0 and  $N-1$ . As a result, one coefficient set  $\{c_0(m), c_1(m), \dots, c_K(m)\}$  is assigned to each segment. Based on segmental interpolation of the characteristic, zero<sup>th</sup> coefficients  $c_0(m)$  are added in, so that for the sequence of compensated digital data  $y_n$  outputted from the compensation circuit 2 the following expression applies:

$$(5) \quad y_n = \sum_{k=0}^K c_k(m) \cdot x_n^k \text{ where } m = \left\lfloor N \cdot \frac{x_n + 1}{2} \right\rfloor,$$

where  $\lfloor \cdot \rfloor$  represents the rounding operation.

The equation (5) for compensation in the compensation circuit 2, and the iterative calculation of coefficients according to equation (3) may be effectively implemented together, as FIG. figure 3 illustrates. In a memory of size  $N \times (K+1)$ , here the coefficient memory system 52,  $N$  sets of  $K+1$  coefficients each  $c_1(m), c_2(m), \dots, c_K(m)$ , and  $c_0(m)$  are stored for the respective  $m = 0, 1, 2, \dots, N-1$ . For each sampling instant, the index  $m$  is derived according to equation (5) from the input signal, i.e., from the applied value for the sequence of digital data  $x_n$ , and assigned to the corresponding coefficient set  $52_0, 52_1, \dots, 52_{N-1}$ , then applied accordingly within the compensation circuit 2. Also in this procedure, the stored value for each coefficient is iteratively improved according to equation (3) and stored in the same memory location.

As shown in FIG. 4, in a certain case the method with segmental interpolation may be simplified with  $N = 2^B$ . For this purpose, it is necessary that the number  $N$  of segments agree with the resolution of the signal or the sequence of digital data  $x_n$ , i.e.,  $N = 2^B$  applies, where  $B$  is the number of bits per sampling value given a signal range between  $-2^{B-1}$  and  $2^{B-1}-1$  and only one coefficient per segment, i.e.,  $K = 0$ .

The circuit of FIG. 3 is thereby reduced to the circuit of FIG. 4 which has, following the index determination device 51 for determining the index  $m$ , a look-up table with  $2^B$  adaptive coefficients  $c_0(m)$  in memory fields  $52_0, \dots, 52_{N-1}$ . In this arrangement, all the multipliers 54 are eliminated so that only the first addition stage with adders  $53_1, \dots$  remains, as described above.

Initial synthetic calculations using a sinusoidal tone as the test signal  $s(t)$  and a mathematical model of the analog-to-digital characteristic with frequencies  $F_s = 40.5$  MHz,  $F_t = 1.84$  MHz, the A/D model with coefficients for the calculation based on  $0.9895x + 0.0028x^2 + 0.024x^3 - 0.0064x^4$  and for compensation  $N = 1$  segments, and a maximum running index of  $m$  with  $K = 4$ , produced significant improvements. After analog-to-digital conversion, the initial value was -60.3 dB, and after compensation the value was 80.9 dB – yielding a significant improvement of 20.5 dB. In the case of one measurement (K3), the improvement found was -47.2 dB after A/D conversion, as compared with -56.3 dB after compensation, giving an improvement of 9.1 dB. The ratio of distortions to outputs after A/D conversion was -46.8 dB, as compared with -55.3 dB after compensation – producing an improvement of 8.4 dB.

In place of a plurality of individual components, as described above, an implementation is also possible in an analogously capable computer chip, or in a monolithically fabricated semiconductor device in the form of an integrated circuit or the like.

Although the present invention has been shown and described with respect to several

preferred embodiments thereof, various changes, omissions and additions to the form and detail thereof, may be made therein, without departing from the spirit and scope of the invention.

What is claimed is:

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